

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Rule 53(b) Divisional Application of:
Shunji NAKAMURA

Serial No.: New (Divisional Application of S.N.10/352,028)

Group Art Unit: **2831** (Expected)

Filed: **February 24, 2004**

Examiner: HA, NGUYEN T (Expected)

For: **CAPACITOR AND METHOD FOR FABRICATING THE SAME AND
SEMICONDUCTOR DEVICE**

Attorney Docket No.: **030086A**

Customer Number: **38834**

INFORMATION DISCLOSURE STATEMENT
PURSUANT TO 37 CFR §1.97(b)

Commissioner for Patents
P.O. Box 1450
Alexandria, Virginia 22313-1450

February 24, 2004

Sir:

This Information Disclosure Statement is being filed in order to comply with Applicant's duty of disclosure under 37 C.F.R. §1.56. The documents listed on the Form PTO-1449 were made of record in parent application Serial No. **10/352,028**.

In the event that any fees are due in connection with the filing of this paper, please charge any fees to Deposit Account No. 50-2866.

Respectfully Submitted,

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	Applicant(s): Shunji NAKAMURA	
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U.S. PATENT DOCUMENTS

Examiner Initial		Document No.	Name	Date	Class	Subclass	Filing Date (If appropriate)
	AA	2002/0056869	Morimoto	05/16/2002	257	313	11/13/2001
	AB	2002/0155626	Park	10/24/2002	438	3	04/18/2002
	AC	6,552,384	Murata et al.	04/22/2003	257	307	07/02/2001
	AD	6,198,617	Sun	03/06/2001	361	301	01/12/1999
	AE	5,978,207	Anderson et al.	11/02/1999	361	311	10/30/1997
	AF						

FOREIGN PATENT DOCUMENTS

		Document No.	Date	Country	Translation (Yes or No)
	AG	11-97535	04/09/1999	Japan	Abstract
	AH				
	AI				
	AJ				
	AK				

OTHER DOCUMENTS

	AL	Hiroshi HORIE et al.; International Electron Device Meeting, pp.946-948, 1996.
	AM	S. NAKAMURA et al.; Symposium on VLSI Technology Digest of Technical Papers, 4A-2, pp.35-36, 1999.
Examiner		Date Considered